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NDS9400A Single P-Channel Enhancement Mode Field Effect Transistor

General Description

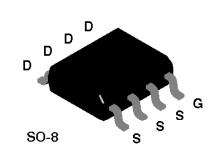
These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulses in the avalanche and commutation modes. These devices are particularly suited for low voltage applications such as notebook computer power management and other battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.

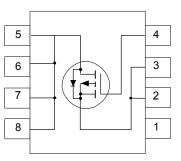
Features

- -3.4A, -30V. $R_{DS(ON)} = 0.13\Omega @ V_{GS} = -10V.$
- High density cell design for extremely low R_{DS(ON)}.
- High power and current handling capability in a widely used surface mount package.

February 1996

Rugged and reliable.





Absolute Maximum Ratings T₄ = 25°C unless otherwise noted

Symbol	Parameter		NDS9400A	Units
V _{DSS}	Drain-Source Voltage		-30	V
V _{GSS}	Gate-Source Voltage		± 20	V
I _D	Drain Current - Continuous	(Note 1a)	± 3.4	A
	- Pulsed		± 10	
P _D	Maximum Power Dissipation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
		(Note 1c)	1	
T _J ,T _{STG}	Operating and Storage Temperature Range		-55 to 150	°C
THERMA	L CHARACTERISTICS			
R _{ØJA}	Thermal Resistance, Junction-to-Ambient (Note 1a)		50	°C/W
R _{eJC}	Thermal Resistance, Junction-to-Ca	Se (Note 1)	25	°C/W

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Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{gs} = 0 V, I _p = -250 μA		-30			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -24 V, V _{GS} = 0 V				-2	μA
			T _J = 55°C			-25	μA
	Gate - Body Leakage, Forward	$V_{gs} = 20 V, V_{ds} = 0 V$				100	nA
	Gate - Body Leakage, Reverse	V _{gs} = -20 V, V _{ps} = 0 V				-100	nA
ON CHAR	ACTERISTICS (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{ps} = V_{qs}, \ I_{p} = -250 \ \mu A$		-1	-1.6	-2.8	V
			T _J = 125°C	-0.85	-1.25	-2.5]
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} = -10 V, I _D = -1.0 A			0.11	0.13	Ω
			T _J = 125°C		0.15	0.21	
		$V_{gg} = -4.5 \text{ V}, \ I_{p} = -0.5 \text{ A}$			0.17	0.2	
			T _J = 125°C		0.24	0.32	
I _{D(on)}	On-State Drain Current	$V_{GS} = -10 \text{ V}, V_{DS} = -5 \text{ V}$		-10			Α
9 _{FS}	Forward Transconductance	V _{DS} = -15 V, I _D = -3.4 A			4		S
DYNAMIC	CHARACTERISTICS						
C _{iss}	Input Capacitance	$V_{DS} = -10 V, V_{GS} = 0 V,$ f = 1.0 MHz			350		pF
C _{oss}	Output Capacitance				260		pF
C _{rss}	Reverse Transfer Capacitance				100		pF
SWITCHI	NG CHARACTERISTICS (Note 2)						
t _{D(on)}	Turn - On Delay Time	$V_{\rm DD}$ = -10 V, I _D = -1 A, V _{GEN} = -10 V, R _{GEN} = 6 Ω			9	40	ns
ţ.	Turn - On Rise Time				21	40	ns
t _{D(off)}	Turn - Off Delay Time				21	90	ns
t _r	Turn - Off Fall Time				8	50	ns
Q _g	Total Gate Charge	$V_{DS} = -10 V,$ $I_{D} = -3.4 A, V_{GS} = -10 V$			10	25	nC
Q _{gs}	Gate-Source Charge	$I_{\rm D} = -3.4 \text{ A}, V_{\rm GS} = -10 \text{ V}$			1.6		nC
Q _{gd}	Gate-Drain Charge				3.4		nC

Symbol	Parameter	Conditions		Тур	Max	Units
DRAIN-SO	OURCE DIODE CHARACTERISTICS AN	D MAXIMUM RATINGS	-			
l _s	Maximum Continuous Drain-Source Diode Forward Current				-1.9	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{gs} = 0 V, I_s = -1.25 A$ (Note 2)		-0.8	-1.3	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, \text{ I}_{\text{F}} = -2.0 \text{ A}, \text{ dI}_{\text{F}}/\text{dt} = 100 \text{ A}/\mu\text{s}$			100	ns
l,,	Reverse Recovery Current			1.9		Α

1. R_{p.4} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{p.C} is guaranteed by design while $\mathrm{R}_{_{\mathrm{BCA}}}$ is determined by the user's board design.

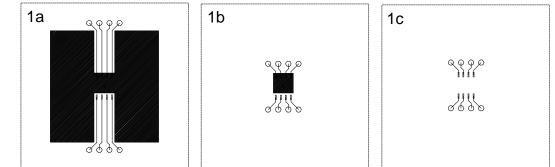
 $P_D(t) = \frac{T_J - T_A}{R_{\theta J} \, \hat{k}^{(1)}} = \frac{T_J - T_A}{R_{\theta J} \, \hat{c}^t R_{\theta C} \hat{k}^{(1)}} = I_D^2(t) \times R_{DS \, (ON)} \hat{\boldsymbol{g}}_{TJ}$

Typical R_{BA} using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

a. 50°C/W when mounted on a 1 \mbox{in}^2 pad of 2oz cpper.

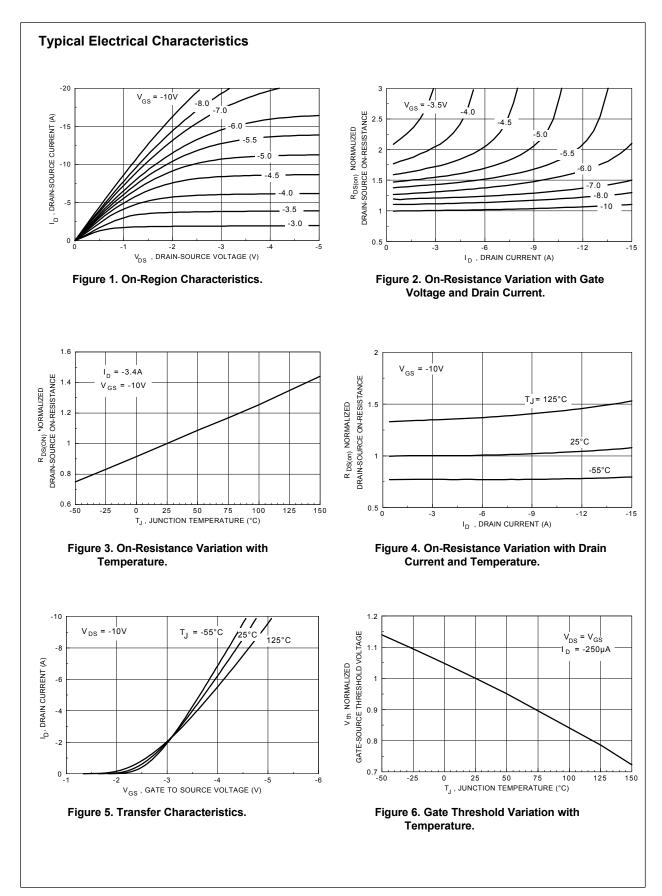
b. 105°C/W when mounted on a 0.04 in² pad of 2oz cpper.

c. 125°C/W when mounted on a 0.006 in² pad of 2oz cpper.

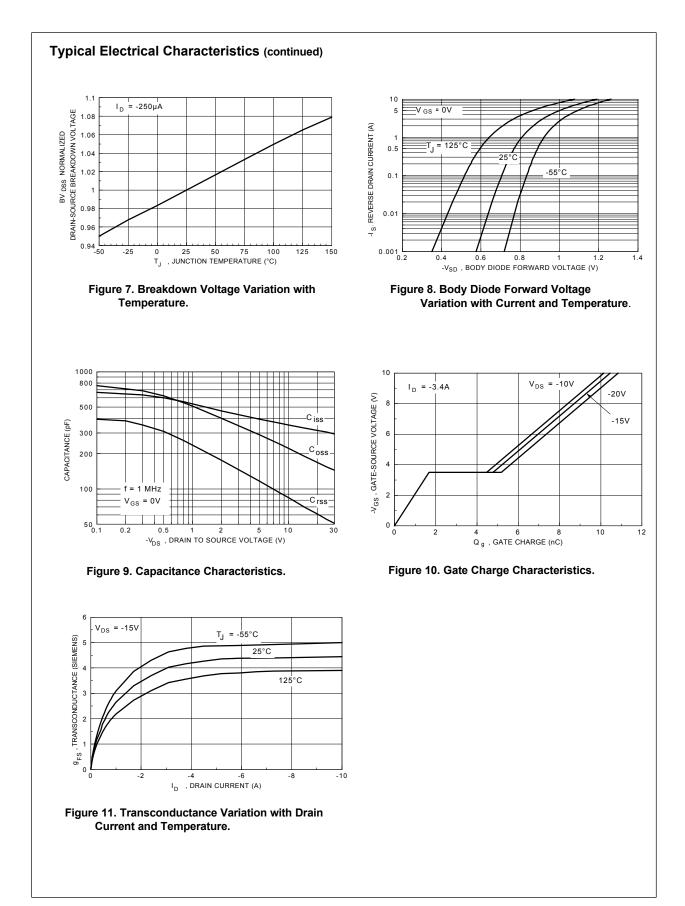


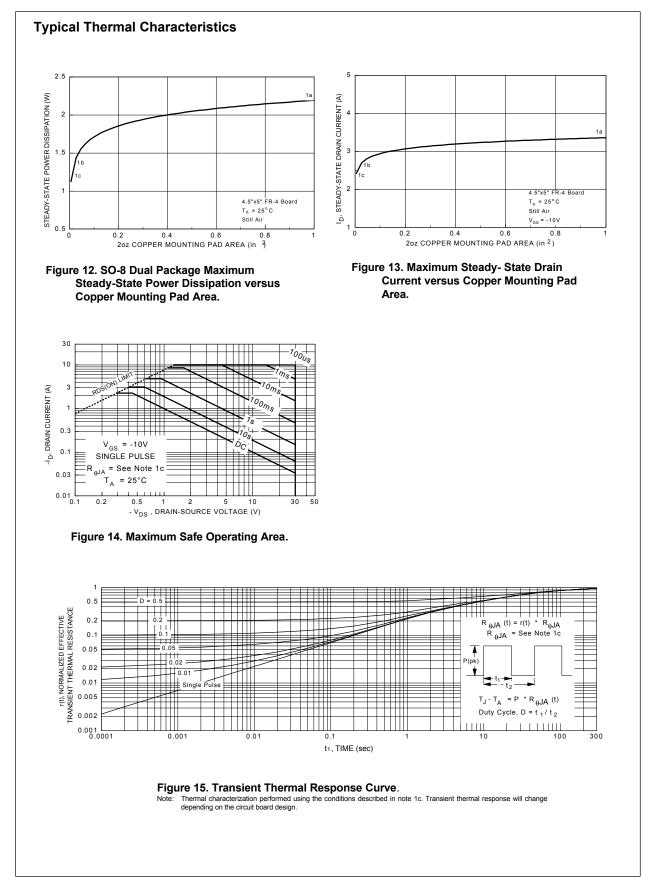
Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2.0%.



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